## INTERNATIONAL STANDARD

ISO 13084

First edition 2011-05-15

## Surface chemical analysis — Secondaryion mass spectrometry — Calibration of the mass scale for a time-of-flight secondary-ion mass spectrometer

Analyse chimique des surfaces — Spectrométrie de masse des ions secondaires — Étalonnage de l'échelle de masse pour un spectromètre de masse des ions secondaires à temps de vol



Reference number ISO 13084:2011(E)



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Published in Switzerland

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ISO 13084 was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 6, *Secondary ion mass spectrometry*.